Robert Hull

List of Publications by Year in descending order

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40 papers

348 citations

8 h-index 18 g-index

41 all docs

41 docs citations

41 times ranked

413 citing authors

#	Article	IF	Citations
1	Development of a Nanoindenter for In Situ Transmission Electron Microscopy. Microscopy and Microanalysis, 2001, 7, 507-517.	0.4	97
2	Investigation of Structural Evolution of Li _{1.1} V ₃ O ₈ by <i>In Situ</i> X-ray Diffraction and Density Functional Theory Calculations. Chemistry of Materials, 2017, 29, 2364-2373.	6.7	40
3	In Situ Studies of the Interaction of Dislocations with Point Defects during Annealing of Ion Implanted Si/SiGe/Si (001) Heterostructures. Microscopy and Microanalysis, 1998, 4, 294-307.	0.4	39
4	Metastable Structures in Al Thin Films Before the Onset of Corrosion Pitting as Observed using Liquid Cell Transmission Electron Microscopy. Microscopy and Microanalysis, 2014, 20, 462-468.	0.4	30
5	Strain compensated In1â^'xGaxAs(x<0.47) quantum well photodiodes for extended wavelength operation. Applied Physics Letters, 1998, 73, 2263-2265.	3.3	23
6	Stochasticity in materials structure, properties, and processingâ€"A review. Applied Physics Reviews, 2018, 5, .	11.3	15
7	Analysis of the three-dimensional ordering of epitaxial Ge quantum dots using focused ion beam tomography. Applied Physics Letters, 2006, 88, 263103.	3.3	9
8	Strain Accommodation and Relief in GeSi / Si Heteroepitaxy. Series on Directions in Condensed Matter Physics, 1999, , 299-367.	0.1	8
9	Growth and characterizations of InP self-assembled quantum dots embedded in InAIP grown on GaAs substrates. Journal of Electronic Materials, 2001, 30, 471-476.	2.2	8
10	Composition and stress fields in undulated Si0.7Ge0.3â·Si(100) thin films. Journal of Applied Physics, 2006, 100, 083510.	2.5	8
11	Modulation of the magnetism in ion implanted MnxGe1 \hat{a} °x thin films by rapid thermal anneal. Journal of Applied Physics, 2010, 108, .	2.5	8
12	Electrochemical memristive devices based on submonolayer metal deposition. APL Materials, 2019, 7, 101121.	5.1	8
13	In situ EC-TEM Studies of Metal Thin Film Corrosion in Liquid Solutions at Elevated Temperatures. Microscopy and Microanalysis, 2018, 24, 254-255.	0.4	7
14	Enhanced magnetic and electrical properties in amorphous Ge:Mn thin films by non-magnetic codoping. Journal of Applied Physics, 2012, 111, 033916.	2.5	6
15	In Situ Transmission Electron Microscopy of High-Temperature Inconel-625 Corrosion by Molten Chloride Salts. Journal of the Electrochemical Society, 2021, 168, 051507.	2.9	6
16	The material dependence of temperature measurement resolution in thermal scanning electron microscopy. Applied Physics Letters, 2013, 102, 113107.	3.3	5
17	Studies of Corrosion of Al Thin Films using Liquid Cell Transmission Electron Microscopy. Materials Research Society Symposia Proceedings, 2013, 1525, 1.	0.1	4
18	Liquid Cell TEM of Al Thin Film Corrosion under Potentiostatic Polarization. Microscopy and Microanalysis, 2015, 21, 973-974.	0.4	4

#	Article	IF	Citations
19	Directed Self-Assembly of Ge Quantum Dots Using Focused Si2+ Ion Beam Patterning. Scientific Reports, 2018, 8, 9361.	3.3	4
20	Nanoscale Tomographic Imaging using Focused Ion Beam Sputtering, Secondary Electron Imaging and Secondary Ion Mass Spectrometry. Microscopy and Microanalysis, 2001, 7, 934-935.	0.4	3
21	Self-Assembled Iii-Phospide Quantum Dots Grown by Metalorganic Chemical Vapor Deposition. Materials Research Society Symposia Proceedings, 1999, 583, 39.	0.1	2
22	Ion-induced Auger Electron Spectroscopy as a Potential Route to Chemical Focused-Ion Beam Tomography. Microscopy and Microanalysis, 2014, 20, 310-311.	0.4	2
23	An In Situ Transmission Electron Microscopy Study of Localized Corrosion on Aluminum. MRS Advances, 2016, 1, 1877-1882.	0.9	2
24	Substrates with Programmable Heater Arrays for In-Situ Observation of Microstructural Evolution of Polycrystalline Films: Towards Real Time Control of Grain Growth. MRS Advances, 2016, 1, 1947-1952.	0.9	2
25	Influence of Controlled Cooling Rates During Thermal Processing of Ti 6% Al 4% V Alloys Using In-Situ Scanning Electron Microscopy. MRS Advances, 2020, 5, 1603-1611.	0.9	2
26	SiGe Epilayer Stress Relaxation: Quantitative Relationships Between Evolution of Surface Morphology and Misfit Dislocation Arrays. Materials Research Society Symposia Proceedings, 2001, 696, 1.	0.1	1
27	Nano-scale Chemistry of Complex Self-Assembled Nanostructures in Epitaxial SiGe Films. Materials Research Society Symposia Proceedings, 2013, 1551, 75-80.	0.1	1
28	Corrosion of Metal Films Observed Using In Situ and Ex Situ Electron Microscopy. Microscopy and Microanalysis, 2014, 20, 1540-1541.	0.4	1
29	In Situ Correlative Microscopy Combining Transmission Electron Microscopy and Secondary Ion Mass Spectrometry. Microscopy and Microanalysis, 2018, 24, 380-381.	0.4	1
30	Accelerated Electromigration Study of Cobalt Thin Films by In-Situ TEM. Microscopy and Microanalysis, 2019, 25, 1902-1903.	0.4	1
31	The effect of cooling conditions on Ti 6%Al 4%V microstructure observed using high-temperature in-situ scanning electron microscopy. Journal of Materials Research, 2021, 36, 717-728.	2.6	1
32	NANOELECTRONICS: SOME CURRENT ASPECTS AND PROSPECTS. , 2003, , .		0
33	Guided Control of Cu2O Nanodot Self-Assembly on SrTiO3 (100). Materials Research Society Symposia Proceedings, 2004, 811, 146.	0.1	0
34	Nano-scale Stress and Compositional Analysis of Epitaxial Si1-xGex/Si (100) Undulated Films. Materials Research Society Symposia Proceedings, 2004, 854, U3.8.1.	0.1	0
35	Heteroepitaxial Self-Assembly of Higher-Complexity Structures By Combining Growth Control with Nanopatterning. Materials Research Society Symposia Proceedings, 2004, 849, 81.	0.1	0
36	Correlation of Nanoscale Structure and Magnetic Properties in Manganese Doped Germanium Dilute Magnetic Semiconductors. Materials Research Society Symposia Proceedings, 2011, 1305, 1.	0.1	0

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37	A Low Electron Voltage Approach to Increase Spatial Resolution of Temperature Mapping in Thermal Scanning Electron Microscopy. Materials Research Society Symposia Proceedings, 2013, 1525, 1.	0.1	O
38	Controlled Nucleation of Ge Islands on Si and Self-Assembly of Nanoscale Island Clusters. International Journal of High Speed Electronics and Systems, 2014, 23, 1420003.	0.7	0
39	New Methods for Measuring Chemistry and Temperature Using Scanning Ion and Electron Beams. Microscopy and Microanalysis, 2016, 22, 610-611.	0.4	0
40	Distributions of kinetic pathways in strain relaxation of heteroepitaxial films. Journal of Materials Research, 2017, 32, 3977-3991.	2.6	О